Rotationally-oriented MoS₂ growth by thermal vapour sulfurization of Mo film

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Abstract

Two-dimensional molybdenum disulphide (MoS₂) film has been synthesized by thermal vapour sulfurization (TVS) of thin Mo film. Figure 1(a) shows transmission electron microscopy (TEM) image of the MoS₂ film transferred on a TEM grid. Selected area electron diffraction (SAED) patterns taken from different spots identified in (a) exhibited nearly identical crystallographic orientations, revealing the rotational alignment of the MoS₂ domains in the film. The film was found to consist of 4~5 layers (Figure 1(b)). The MoS₂ film was also characterized by Raman spectroscopy. As shown in Figure 2(a), the two Raman modes E_{2q}^1 and A_{1q} are observed at a separation of about 25 cm⁻¹, indicating multilayer formation [1]. MoS₂field-effect-transistor channel (FET) fabricated on a SiO₂/Si substrate exhibits ntype semiconducting behaviour (Figure 2(c)), which is consistent with previous reports [2, 3]. Two-terminal FETs exhibited electron mobility ranged from 0.1 to 2.9 cm²V⁻¹s⁻¹ at room temperature which is larger than previously reported values of TVS-grown MoS₂ [4, 5]. We also tested gassensing properties of the FET, and it was found to exhibit resistivity change by an order of magnitude to 7 ppb of NO₂ in N₂. This research was partly supported by JST CREST Grant Number JPMJCR15F1, Japan.

References

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Figures

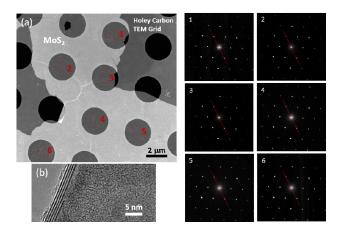


Figure 1: (a) TEM image of MoS₂ (bright region) and SAED patterns taken from the corresponding areas labelled in the image. (b) TEM image of a folded MoS₂ film.

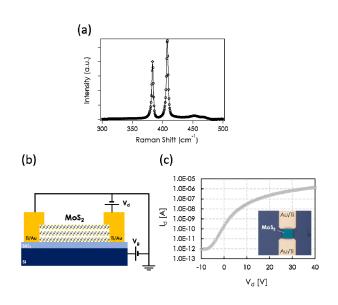


Figure 2: (a) Raman spectrum of the MoS_2 film. (b) Schematic illustration of a MoS_2 -FET. (c) Drain current, I_d , as a function of back-gate voltage, V_g , of a MoS_2 -FET. Inset shows an optical image of the MoS_2 -FET.